

ABSTRACT

A test selector that multiplexes different test structures (202) to an adjacent probe pad (206) in dependence on the probe voltage. In addition, a scribeline test circuit is disclosed that includes a test selector circuit located in a single scribeline portion between two adjacent die locations. Multiple test structures and at least one probe pad also are located in the single scribeline portion. The test selector circuit makes an electrical connection from the probe pad to a selected one of the test structures depending upon a voltage applied at the probe pad.